IDS 12/12/03

Form PTO-	1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2461			SERIAL NO. 10/734,5		
		LIST OF ART CITED (Use several sheets		ιτ	APPLICANT: Eugene Marsh et al.						
					FILING DATE PRIORITY Augu	ıst 27, 200	~ I	GROUP PRIORITY 2822			
U.S. PATEN	NT DOC	UMENTS			·		_				
*Examiner's tnitials		Document Number	Date	Name		Class	Subclass		g Date ropriate		
KBD	AA	5,925,411	07/1999	van dė Ven et al.		427	248.1				
	AB	6,270,572 B1	08/2001	Kim et al.	117	93					
	AC	6,301,434 B1	10/2001	McDiarmid et al.		392	416				
	AD.	6,305,314 B1	10/2001	Sneh et al.		118	723				
	Æ	6,355,561 B1	03/2002	Sandhu et al.		438	676				
	AF	6,403,156 B2	06/2002	Jang et al.	427	255.34					
	AG	6,426,307 B2	07/2002	Lim	438	778					
	AH	6,468,924 B2	10/2002	Lee et al.	438	763		, .			
∜	AJ	6,475,286 B1	11/2002	Frijlink	118	719	9				
FOREIGN F	ATENT	DOCUMENTS									
		Document Number	Date .	Country		Class	SubclasS		lation		
	ىم							Yes	No		
	AK										
	AL										
OTHER RE	FEREN	CES (including Author,	Title, Date, Pe	rtinent Pages, Etc.)							
	АМ			· · · · · · · · · · · · · · · · · · ·							
						······					
-	AN										
	AO .										
	.					<del></del>					
EXAMINER	Thy	DATE CONSIDE	RED 2//	15/2005							
EXAMINER: considered. I	Initial if	reference considered, when	ther or not citatio	n is in conformance with MP applicant.	EP 609; Draw line th	rough citat	ion if not in (	conformance	and not		

Form PTO-1449 ATTY, DOCKET NO. U.S. DEPARTMENT OF COMMERCE SERIAL NO. PRIORITY 10/229,887 PATENT AND TRADEMARK OFFICE MI22-2461 LIST OF ART CITED BY APPLICANT APPLICANT: Eugene Marsh et al. (Use several sheets if necessary) FILING DATE **GROUP** PRIORITY August 27, 2002 PRIORITY 2822 **U.S. PATENT DOCUMENTS** Date Class Subclass Filing Date **Document** Name initials Number If Appropriate 6,482,262 B1 11/2002 Elers et al. 117 84 03/2003 6,534,395 B2 Werkhoven et al. 438 627 6,585,823 B1 07/2003 Van Wijck 117 89 AD 6,586,343 B1 07/2003 Ho et al. 438 758 ΑE 20010024387 09/2001 Raaijmakers et al. 365 200 AF 20010041250 11/2001 Werkhoven et al. 428 212 AG 20010050039 A1 12/2001 Park 117 102 AH 20010054381 A1 12/2001 Umotoy et al. 715 118 6,613,587 81 09/2003 Carpenter et al. 345 473 FOREIGN PATENT DOCUMENTS Class Document Date Country SubclasS Translation Yes No N AK AL, OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AM AN AO DATE CONSIDERED \*EXAMINER: Install if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ATTY, DOCKET NO. Form PTO-1449 U.S. DEPARTMENT OF COMMERCE SERIAL NO. PRIORITY 10/229,887 PATENT AND TRADEMARK OFFICE MI22-2461 LIST OF ART CITED BY APPLICANT APPLICANT: Eugene Marsh et al. (Use several sheets if necessary) **FILING DATE GROUP** PRIORITY August 27, 2002 PRIORITY 2822 **U.S. PATENT DOCUMENTS** Subclass Filing Date If Appropriate Initials Number 04/24/02 10/132,003 Dando et al. (as filed) AB 10/132,767 Dando et al. (as filed) 04/24/02 AC 10/150,388 Mardian et al. (as filed) 05/17/02 AD 6,620,253 B1 09/2003 369 Dando et al. 124.07 ΑE 10/163,689 Derderian et al. (as filed) 06/05/02 AF 10/208,314 Castrovillo et al. (as filed) 07/29/02 AG 10/222,282 Sarigiannis et al. (as filed and amended) 08/15/02 AH 10/222,304 Sarigiannis et al. (as filed) 08/15/02 FOREIGN PATENT DOCUMENTS Class **Document** Date Country Translation Subclas9 Number Yes No N AK OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AO DATE CONSIDERED EXAMINER \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ATTY, DOCKET NO. U.S. DEPARTMENT OF COMMERCE SERIAL NO. Form PTQ-1449 MI22-2461 10/734,999 PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT APPLICANT: Micron Technology, Inc. (Use several sheets if necessary) JAN 1 2 2004 **FILING DATE GROUP** Unknown 2822 December 12, 2003 RADEM U.S. PATENT DOCUMENTS Class Subclass Filing Date Document Number Name \*Examiner's Date If Appropriate Initials 03/1999 Gadgil et al. 118 715 5,879,459 10/1999 427 255.32 5,972,430 DiMeo, Jr. et al. AC 729 6,174,377 B1 01/2001 Doering et al. 118 03/2001 438 685 6,200,893 B1 Sneh 438 648 6,287,965 B1 09/2001 Kang et al. 729 118 05/2002 6,387,185 B2 Doering et al. 704 05/2002 438 6,391,785 B1 Satta et al. 715 6,451,119 B2 09/2002 Sneh et al. 118 438 685 6,451,695 B2 09/2002 Sneh FOREIGN PATENT DOCUMENTS Class Date Country Subclass Translation Number Nσ 01/27347 A1 04/2001 WO 16 44 AK 01/29280 A1 04/2001 WO 16 32 01/29893 A1 04/2001 WO 21 768 OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AN ю EXAMINER DATE CONSIDERED 2/15/2005 XAMINER: tritial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

_	
	PO \$490, 18
	a cook Ilist
	JAN 1 2 2004 E. TRADEMARK
	U.S. PATENT DOCUMEN
Ш	

## U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY, DOCKET NO. MI22-2461

SERIAL NO. 10/734,999

OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: Micron Technology, Inc.

FILING DATE

GROUP

J.S. PATEN	VT DOO	UMENTS				,			_	
Examiner's Initials		Document Number	Date	Name		Class	Subclas		ng Date propriate	
VBP	A	6,475,276 B1	11/2002	Elers et al.		117	84			
	AB	6,475,910 B1	11/2002	Sneh		438	685			
	AC	6,589,886 B2	07/2003	Kim et al.		438	758		•	
	AE 6,690,251 B2  AE 6,602,784 B2  AF 6,630,401 B2		07/2003	Kang et al. Sneh		257	310			
			08/2003			438	680			
			10/2003	Sneh		438	680			
	AG	6,638,862 B2	10/2003	Sneh		438	685			
	АН	6,664,192 B2	12/2003	Satta et al.		438	704			
V	AJ	2002/0086111 A1	07/2002	Byun et al.		427	255.394	•		
OREIGN P	ATENT	DOCUMENTS	.,							
		Document Number .	Date	, Country		Class	Subclas9	Tran	Translation	
11.0D								Yes	No.	
KBD	~	01/66832 A2	09/2001	wo		25	14	-		
-	AX.		<u> </u>			_			<u> </u>	
	AL							1	<u> </u>	
THER RE	FEREN	CES (including Author	, Title, Date, Pe	ertinent Pages, Etc.)						
	м									
						•				
	AN			<del> </del>	_ <del>-</del>		<del> </del>	<del></del>		
			· · · · · · · · · · · · · · · · · · ·							
	40					- MAT		<del> </del>		
				<del></del>						
XAMINER		DATE CONSIDE	RED . /	5/2005			····			
~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~			9//	C / 787 S						

FORMPTO	1449		J.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY, DOCKET NO. MI22-2461			SERIAL NO. 10/734,999			
	100 Sept. 100 Se	LIST OF ART CITED		vт	APPLICANT:	: Micron Technology, Inc.					
JAN 1 2 2	1004 8.	,		FILING DATE December 12,		2000			GROUP <del>-Unknow</del> n		
U.S. PATEN	IT DOC	UMENTS									
*Examiner's Initials		Document Number	Date	Name		Class	Su	obclass		g Date propriate	
KED	18D * 2002/0108714 A1		08/2002	Doering et al.		156	345.51				
	AB	2002/0187256 A1	12/2002	Elers et al.		427	99				
	AC	2003/0031807 A1	02/2003	Elers et al.		427	56:	9			
	AD	2003/0032281 A1	02/2003	Werkhoven et al.		438	64	0			
	AE	2003/0129826 A1	07/2003	Werkhoven et al.		438	627				
<b>V</b>	AF	2003/0183171 A1	10/2003	Sneh et al.	*	118	724				
	AG									,	
	AH										
	A		·								
FOREIGN P	ATENT	DOCUMENTS								•	
		Document Number	Date	Country		Class	Gub	oclas6	Trans		
	AJ .			1	,			十	Yes	No	
	AK							$\top$			
	AL.									•	
OTHER RE	FEREN	CES (including Author,	Title. Date, Pe	ertinent Pages, Etc.)					ا ــــــــــــــــــــــــــــــــــــ	<del>-,,,-</del>	
	AM				<u> </u>		-				
	-							<del></del>	<del></del>		
	AN				<del></del>						
	ŀ										
	AO										
	ŀ			·							
EXAMINER		DATE CONSIDER	RED 2/.	15/2005							
EXAMINER: considered in	EXAMINER: Initial/s reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered include copy of this form with next communication to applicant.										

Form PTO-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE						ENT OF COMMERCE	ATTY. DOCKET NO. SERIAL NO. 10/734,999						
O V	LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)							APPLICANT: Micron Technology, Inc.					
or V	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)  FILING DATE December 12,										122		
U.S.	U.S. PATENT DOCUMENTS												
*Examiner's Document Initials Number			Date	Name		Class	Subclass		Filing Date If Appropriate				
M	5D	AA	6,0	15,597	01/2000	David		427	577				
		AB	6,1	97,120	03/2001	David		118	716				
		AC	6,4	82,476	11/2002	Liu		427	535				
		AD	6,6	20,723	09/2003	Byun		438	627				
		AE	6,6	96,157	02/2004	David		428	408				
		AF	6,6	96,368	02/2004	Derraa et al.		438	761				
		AG	6,7	20,027	04/2004	Yang et al.		427	123				
•		АН	6,72	27,169	04/2004	Raaijmakers et al.		438	622				
	AJ 6,746,952		46,952	06/2004	Derraa et al.	· ·	438	627		•			
FOR	EIGN F	ATEN	T DOC	UMENTS									
	Document Number			Date	Country		Class	Subclas	ıs		lation		
KR	$\overline{\mathcal{D}}$	A)	wo	0 04/011693 A1	02/2004	WIPO (Micron Technology, Inc.)		16	44		Yes	No	
		AK											
		AL				· · · · · · · · · · · · · · · · · · ·							
отн	ER RE	FEREN	ICES (	including Author,	Title, Date, Pe	rtinent Pages, Etc.)		<u></u>				-	
		АМ											
						<del></del>							
		AN											
									-		•		
		AO	AO							•	-		
EXAN	AINER/	Thon	1.	DATE CONSIDER	RED 2//	5/2005		-					
EXA consid	EXAMINER: Initiat it reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.												

SERIAL NO. Form PTO-1449 ATTY. DOCKET NO. U.S. DEPARTMENT OF COMMERCE MI22-2461 10/734,999 PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT APPLICANT: Micron Technology, Inc. (Use several sheets if necessary) **FILING DATE GROUP** December 12, 2003 <del>1762</del>-**U.S. PATENT DOCUMENTS** Date Name Class Subclass Filing Date Initials Number If Appropriate 6,753,271 B2 06/2004 AA Sarigiannis et al. 438 785 2003/0143328 A1 07/2003 AB Chen et al. 255.28 427 05/2003 AC 2003/0085424 A1 Bryant et al. 257 347 2004/0137728 A1 07/2004 ΑD Gallagher et al. 438 689 ΑE AF ΑН ΑI FOREIGN PATENT DOCUMENTS Document Date Class Country SubctasS Translation Number Yes No AJ AK OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AN AO EXAMINER DATE CONSIDERED \*EXAMINER: Initigate reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.